

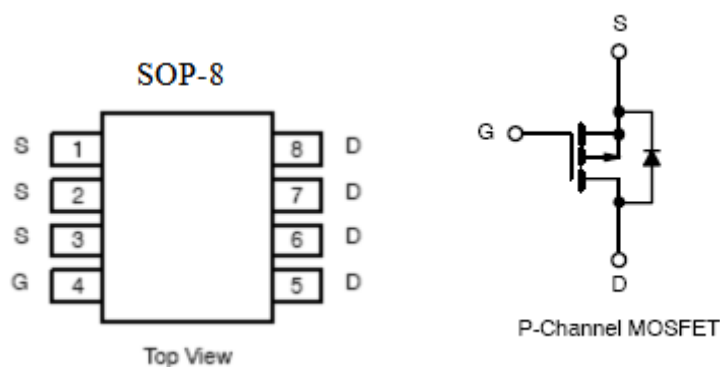
## 1. Features

- n  $R_{DS(on)}=19m\Omega(\text{typ}) @ V_{GS}=10 \text{ V}$
- n Super low gate charge
- n Green device available
- n Excellent Cdv/dt effect decline
- n Advanced high cell density trench technology

## 2. Description

The KPE4703A is the high cell density trenched P-ch MOSFET's, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications. The KPE4703A meet the RoHs and Green Product requirement.

## 3. Symbol



#### 4. Absolute maximum ratings

( $T_A=25^{\circ}\text{C}$ , unless otherwise noted)

Parameter	Symbol	Rating	Units
Drain-source voltage	$V_{DSS}$	-30	V
Gate-source voltage	$V_{GS}$	$\pm 20$	V
Continuous drain current $V_{GS}$ @-10V <sup>1</sup>	$I_D$	$T_A=25^{\circ}\text{C}$	-8.0
		$T_A=70^{\circ}\text{C}$	-6.4
Pulsed drain current <sup>2</sup>	$I_{DM}$	-50	A
Single pulse avalanche energy <sup>3</sup>	EAS	96.8	mJ
Avalanche current	$I_{AS}$	-38	A
Total power dissipation <sup>4</sup>	$P_D$	$T_A=25^{\circ}\text{C}$	3.1
		$T_A=70^{\circ}\text{C}$	2
Storage Temperature Range	$T_{STG}$	-55 to 150	$^{\circ}\text{C}$
Operating Junction Temperature Range	$T_J$	-55 to 150	$^{\circ}\text{C}$

#### 5. Thermal characteristics

Parameter	Symbol	Typ	Max	Units
Thermal resistance, junction-ambient <sup>1</sup>	$R_{\theta JA}$	-	75	$^{\circ}\text{C}/\text{W}$
Thermal resistance, junction-ambient ( $t \leq 10\text{s}$ )		-	40	
Thermal resistance, Junction-case <sup>1</sup>	$R_{\theta JC}$	-	24	

## 6. Electrical characteristics

(T<sub>J</sub>=25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-Source breakdown voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA	-30	-	-	V
BV <sub>DSS</sub> Temperature coefficient	$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Reference to 25 °C, I <sub>D</sub> =-1mA	-	-0.021	-	V/°C
Static drain-source on- resistance <sup>2</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-6A	-	19	24	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4A	-	27	32	
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA	-1	-	-2.5	V
V <sub>GS(th)</sub> Temperature coefficient	$\Delta V_{GS(th)}$		-	4.5	-	mV/°C
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	-	-	-1	μA
		V <sub>DS</sub> =-24V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C	-	-	-5	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
Forward transconductance	g <sub>FS</sub>	V <sub>DS</sub> =-5V, I <sub>D</sub> =-6A	-	15	-	S
Gate resistance	R <sub>g</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1.0MHz	-	12	-	Ω
Total gate charge(-4.5V)	Q <sub>g</sub>	V <sub>DS</sub> =-15V, V <sub>GS</sub> =-4.5V I <sub>D</sub> =-6A	-	12.2	-	nC
Gate-source charge	Q <sub>gs</sub>		-	5.0	-	
Gate-drain charge	Q <sub>gd</sub>		-	5.0	-	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =-15V, R <sub>G</sub> =3.3Ω, V <sub>GS</sub> =-10V I <sub>D</sub> =-6A	-	4.5	-	ns
Rise time	t <sub>r</sub>		-	15	-	
Turn-off delay time	t <sub>d(off)</sub>		-	40	-	
Fall time	t <sub>f</sub>		-	19.4	-	
Input capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =-15V F=1.0MHZ	-	1310	-	pF
Output capacitance	C <sub>oss</sub>		-	190	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	162	-	
Diode characteristics						
Continuous source current <sup>1,5</sup>	I <sub>S</sub>	V <sub>G</sub> =V <sub>D</sub> =0V, Force current	-	-	-8	A
Pulsed source current <sup>2,5</sup>	I <sub>SM</sub>		-	-	-40	A
Diode forward voltage <sup>2</sup>	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =-1A, T <sub>J</sub> =25°C	-	-	-1.3	V
Reverse recovery time	t <sub>rr</sub>	I <sub>F</sub> =-6A, dI/dt=100A/us, T <sub>J</sub> =25°C	-	16	-	nS
Reverse recovery charge	Q <sub>rr</sub>		-	6.1	-	nC

Note:1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

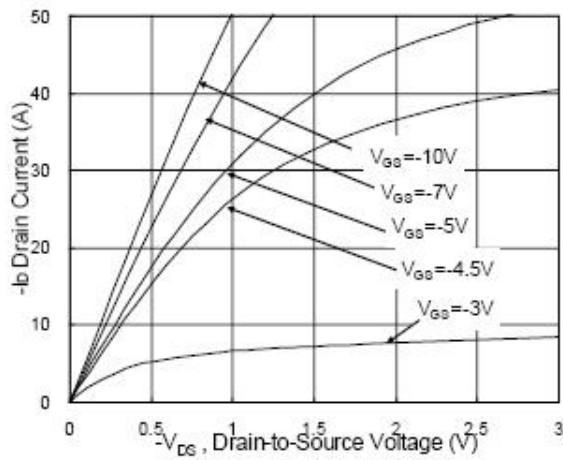
2. The data tested by pulsed, pulse width ≦ 300us, duty cycle ≦ 2%.

3. The EAS data shows Max.rating. The test condition is V<sub>DD</sub>=-25V, V<sub>GS</sub>=-10V, L=0.1mH, I<sub>AS</sub>=-44A.

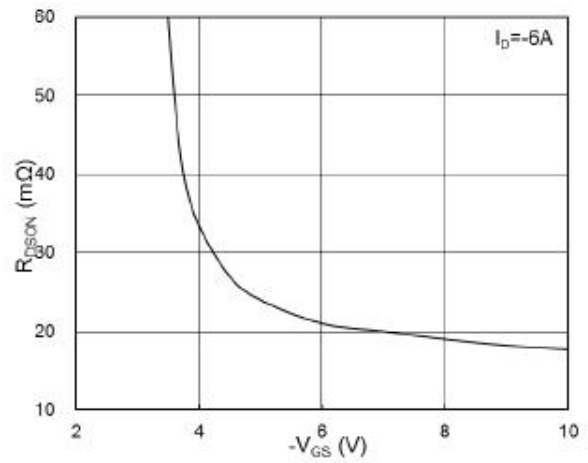
4. The power dissipation is limited by 150 °C junction temperature.

5. The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

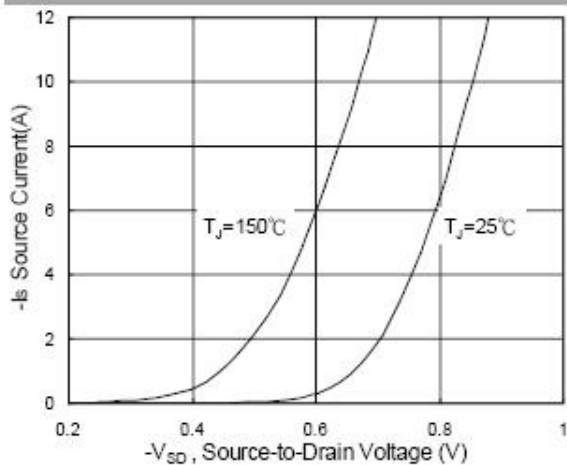
**6. Test circuits and waveforms**



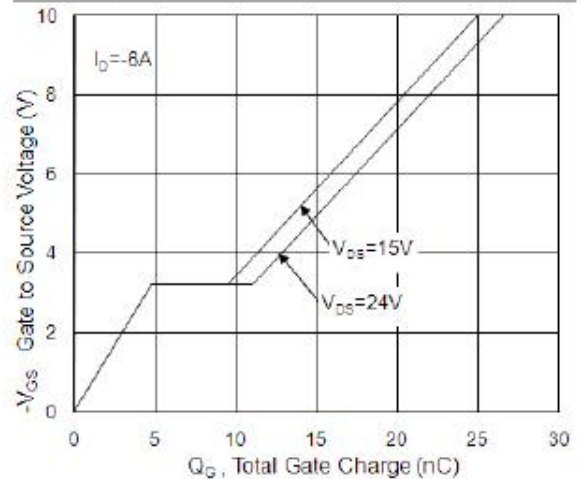
**Fig.1 Typical Output Characteristics**



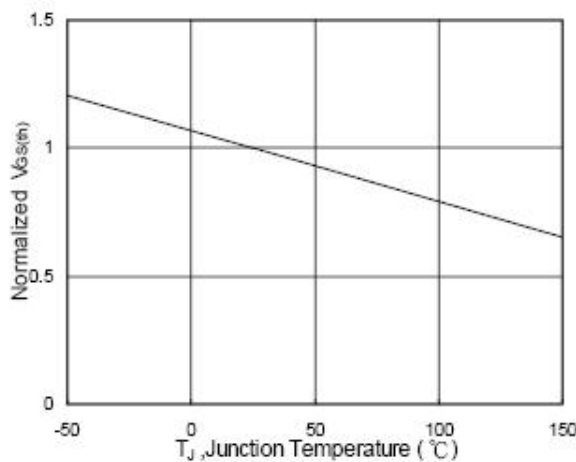
**Fig.2 On-Resistance v.s Gate-Source**



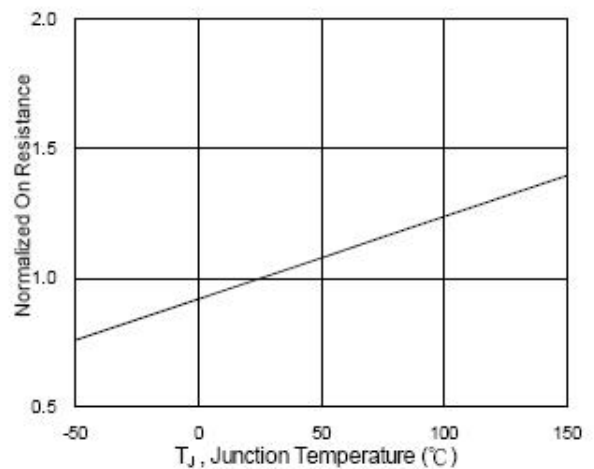
**Fig.3 Forward Characteristics of Reverse**



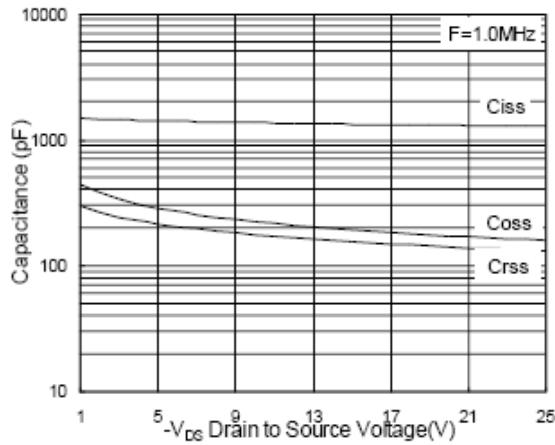
**Fig.4 Gate-Charge Characteristics**



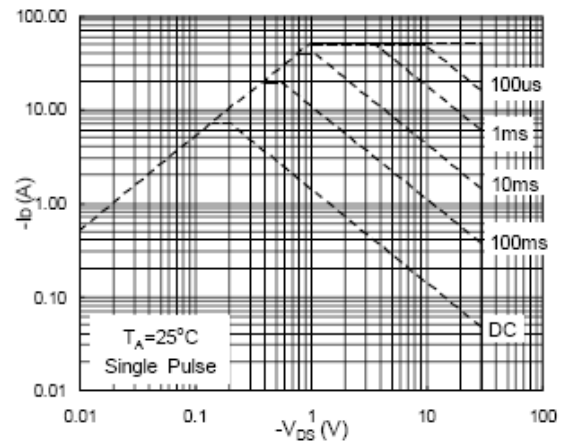
**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**



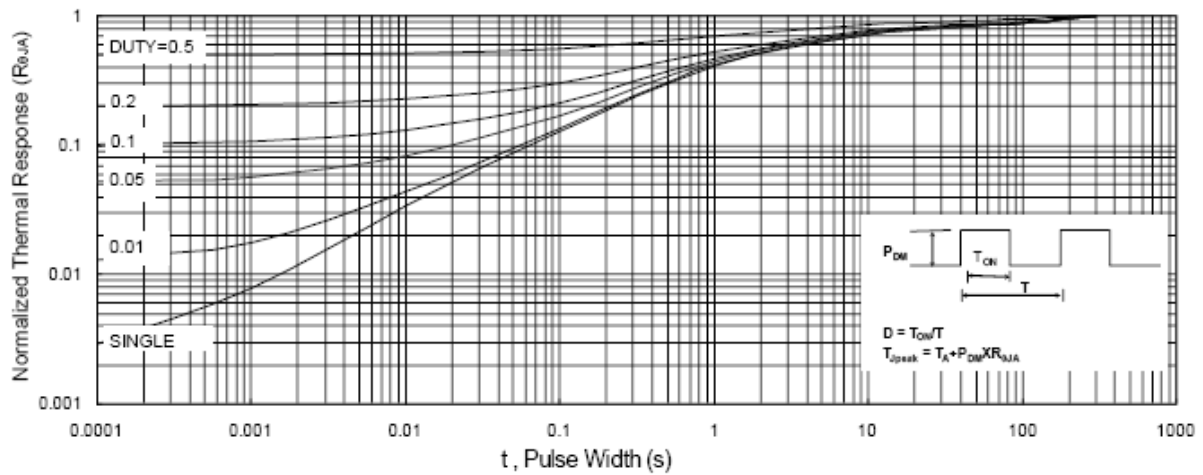
**Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$**



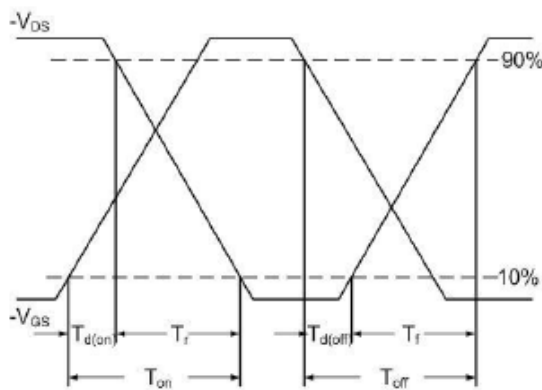
**Fig.7 Capacitance**



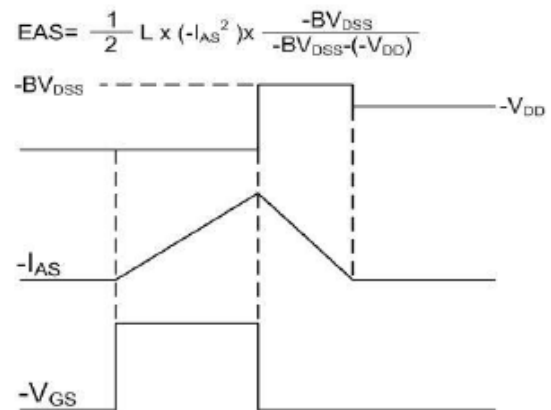
**Fig.8 Safe Operating Area**



**Fig.9 Normalized Maximum Transient Thermal Impedance**



**Fig.10 Switching Time Waveform**



**Fig.11 Unclamped Inductive Switching Waveform**